

Search Notes**Application/Control No.**

10/066,188

Examiner

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Applicant(s)/Patent under Reexamination

TEIG ET AL.

Art Unit

2825

SEARCHED

Class	Subclass	Date	Examiner
716	12	12/30/2005	JSL
716	7	12/30/2005	JSL
716	9	12/30/2005	JSL
716	10	12/30/2005	JSL
716	11	12/30/2005	JSL
716	13	12/30/2005	JSL
716	14	12/30/2005	JSL
716	18	12/30/2005	JSL
716	3	12/30/2005	JSL

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST [USPAT;US- PGPUB;EPO;JPO;DERWENT;IBM_T DB]	12/30/2005	JSL

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
716	3,7,9	12/30/2005	JSL
716	10-14	12/30/2005	JSL
716	18	12/30/2005	JSL